

## Search Notes



**Application/Control No.**

10/626,270

**Examiner**

TAN X. DINH

**Applicant(s)/Patent under  
Reexamination**

YAMASHITA, SATOSHI

## **Art Unit**

2627

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner